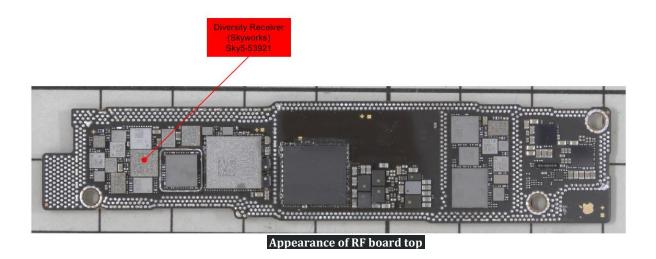
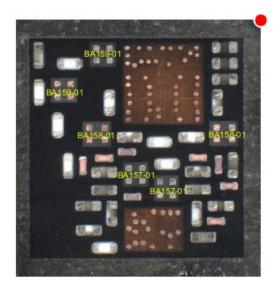
EXHIBIT 2

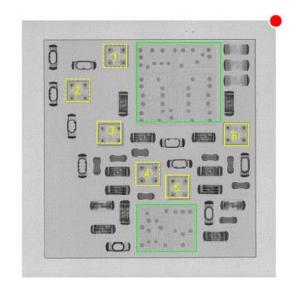
US Patent No. 7,758,979 (Claim 6) vs. Skyworks Sky5 53921 on the RF board of iPhone16e

Disassembling the iPhone 16e shows that it includes the Skyworks RF module, Sky5 53921. This module is an exemplary Accused Product.

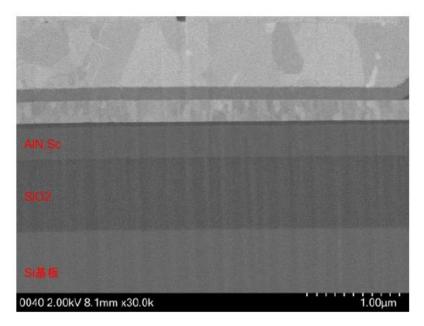


The Sky5 53921 module contains six BAW filters (shown in below X-Ray image outlined in yellow dashed lines). There are three different BAW filter chips – BA157-01, BA158-01, and BA159-01.





EDX testing demonstrates that each of the BAWA testing includes a piezoelectric thin film comprising an aluminum nitride containing scandium. (See, e.g., below SEM image)



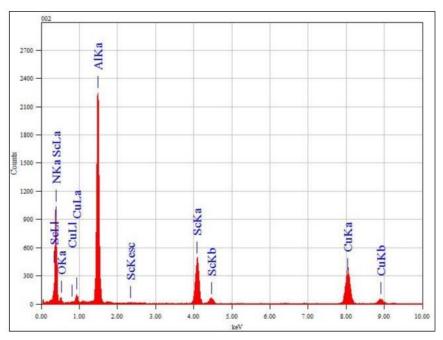
The scandium content ratio for each of these BAW filters is in the range of 10 atom% to 35 atom% or 40 atom% to 50 atom% on an assumption that a total amount of a number of atoms of the scandium and of aluminum in the aluminum nitride thin film is 100 atom%.

The below charts and scandium content ratio analyses provide the results for each of the BAW filters in the above exemplary Accused Product.

Additional Accused Products include all Skyworks modules with one or more BAW filters that include a piezoelectric thin film comprising an aluminum nitride containing scandium at a concentration within the above ranges. By way of example, these include the Sky5 04122, Sky5 0313 6943 2326, Sky5 04418, and Sky5 0313 4688 2326 modules included in the iPhone 15 Pro Max and the Sky5 144102 module included in the iPhone 13 Pro Max.

'979 Patent	Sky5 53921 (BA159-01 BAW Filters)
6. A piezoelectric thin film comprising an	As indicated in the below EDX results and
aluminum nitride thin containing	shown in the above SEM imaging, Sc, Al,
scandium,	and N, were detected in the components
	constituting the piezoelectric thin film,
a content ratio of the scandium being in a	When the total number of atoms of
range of 10 atom % to 35 atom % or 40	scandium and aluminum is 100 atom%, the
atom % to 50 atom % on an assumption	scandium content ratio is 19.76 atom%.
that a total amount of a number of atoms	
of the scandium and a number of atoms of	That is within the range of 10 to 35 atom%.
aluminum in the aluminum nitride thin	
film is 100 atom %.	

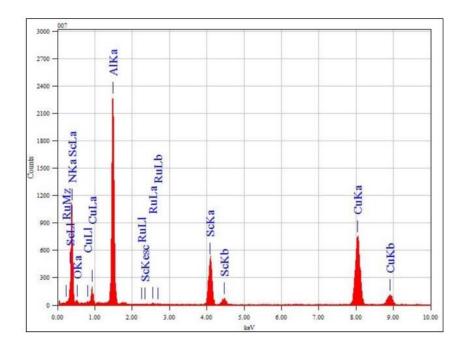
Sky5 53921 (BA159-01 BAW Filters) EDX analysis results



Element	Mass%	Atom%
AI K	70.89	80.24
Sc K	29.11	19.76
Total	100	100

	T #: /1Q
'979 Patent	#:48ky5 53921 (BA158-01 BAW Filters)
6. A piezoelectric thin film comprising an	As indicated in the below EDX results and
aluminum nitride thin containing	shown in the above SEM imaging, Sc, Al,
scandium,	and N, were detected in the components
Scandiani,	constituting the piezoelectric thin film,
	constituting the piezoelectric thin film,
a content ratio of the scandium being in a	When the total number of atoms of
range of 10 atom % to 35 atom % or 40	scandium and aluminum is 100 atom%, the
atom % to 50 atom % on an assumption	scandium content ratio is 20.63 atom%.
that a total amount of a number of atoms	
of the scandium and a number of atoms of	That is within the range of 10 to 35 atom%.
	That is within the range of 10 to 33 atom/o.
aluminum in the aluminum nitride thin	
film is 100 atom %.	

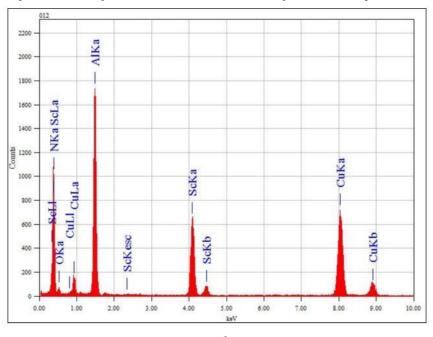
Sky5 53921 (BA158-01 BAW Filters) EDX analysis results



Element	Mass%	Atom%
AI K	69.72	79.37
ScK	30.28	20.63
Total	100	100

'979 Patent	#: Sky5 53921 (BA157-01 BAW Filters)
6. A piezoelectric thin film comprising an	As indicated in the below EDX results and
aluminum nitride thin containing	shown in the above SEM imaging, Sc, Al,
scandium,	and N, were detected in the components
	constituting the piezoelectric thin film,
a content ratio of the scandium being in a	When the total number of atoms of
range of 10 atom % to 35 atom % or 40	scandium and aluminum is 100 atom%, the
atom % to 50 atom % on an assumption	scandium content ratio is 30.26 atom%.
that a total amount of a number of atoms	
of the scandium and a number of atoms of	That is within the range of 10 to 35 atom%.
aluminum in the aluminum nitride thin	
film is 100 atom %.	

Sky5 53921 (BA157-01 BAW Filters) EDX analysis results



Element	Mass%	Atom%
AI K	58.03	69.74
Sc K	41.97	30.26
Total	100	100